

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10082431	02/22/2002	324	7.3	2858	N. Le

\*\*APPLICANTS: Zhang Wei;

He

\*\*CONTINUING DATA VERIFIED:

None on

\*\* FOREIGN APPLICATIONS VERIFIED:

None on

PG-PUB	DO NOT PUBLISH <input checked="" type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		ATTORNEY DOCKET NO	
35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		SUN-P6557	
Verified and Acknowledged Examiners's initials		ah	
TITLE : Integrated electromigration length effect testing method and apparatus			
U.S. DEPT. OF COMM. / PAT. & TM. PTO-436L (Rev. 12-94)			

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Assistant Examiner Amy He	
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drawn	Fig. Drawn
			Print Fig
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		Application Examiner	
		<b>PREPARED FOR ISSUE</b>	
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